Search Notes



Application/Control No.	Applicant(s)/Patent Under Reexamination
10754174	LAU ET AL.
Examiner	Art Unit
John P Lacyk	3735

SEARCHED							
Class	Subclass	Date	Examiner				
600	16, 37	2/22/05	NV				
36	50.1, 110	2/22/05	NV				
385	100, 105	2/22/05	NV				
24	387	2/22/05	NV				
Updated	above	3/27/08	JPL				
Updated	above	5/23/08	JPL				

SEARCH NOTES				
Search Notes	Date	Examiner		
Inventorshiip	2/22/05	NV		
East	2/22/05	NV		
West	2/22/05	NV		
Consulted with Ex. S. Gilbert	2/22/05	NV		

INTERFERENCE SEARCH					
Class	Subclass	Date	Examiner		
Interference		5/27/08	JPL		
Search					
History					
Printout					

U.S. Patent and Trademark Office Part of Paper No.: 20080527